



Product/Process Change Notice - PCN 23_0247 Rev. -

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This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title:	ADATE334 Die Revision
Publication Date:	04-Dec-2023
Effectivity Date:	07-Mar-2024 <i>(the earliest date that a customer could expect to receive changed material)</i>
Revision Description:	Initial Release.

Description Of Change:

Biased ESD results changed from +/-1kV to +/-2kV.

Reason For Change:

Revised ESD protection architecture for improved performance and robustness.

Impact of the change (positive or negative) on fit, form, function & reliability:

No change to fit, form, or function when operated within data sheet specification. Improved reliability.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

[ADI_PCN_23_0247_Rev_-ADATE334 Qualification Report.pdf...](#)

Note: If applicable, the device material declaration will be updated due to material change.

ADI Contact Information:

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:	Europe:	Japan:	Rest of Asia:
PCN_Americas@analog.com	PCN_Europe@analog.com	PCN_Japan@analog.com	PCN_ROA@analog.com

Appendix A - Affected ADI Models:

Added Parts On This Revision - Product Family / Model Number (1)

ADATE334 / ADATE334KBCZ

Appendix B - Revision History:			
Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	04-Dec-2023	07-Mar-2024	Initial Release.